Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/750,580	HIGASHI ET AL.	
Examiner	Art Unit	

Thinh T. Nguyen

2818

SEARCHED					
Subclass	Date	Examiner			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST	7/7/2007	TTN		
ALL REFRENCES CITED IN PARENT CASE US PATENT 7,015,457 AND 7,071,566	7/8/2007	TTN		